Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,447	BASU ET AL.	
Examiner	Art Unit	
Dienane M. Bayard	2141	

SEARCHED			
Class	Subclass	Date	Examiner
709	219	1/26/2007	DB
709	203	1/26/2007	DB
709	226	1/26/2007	DB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEAR (INCLUDING SI	CH NOTES EARCH STRATEGY	·)
	DATE	EXMR
east	12/26/2007	DB
Inventor's search	12/26/2007	DB